

Dr. Ronald Green is an electronics engineer at the U.S. Army Research Laboratory (ARL), Sensors and Electron Devices Directorate (SEDD). Ron's research focus includes reliability physics of wide bandgap (WBG) semiconductors, experimental validation and analyses of silicon carbide (SiC) and gallium nitride (GaN) power devices, characterization and testing of WBG power modules, and development of reliability test methods for standardization of WBG semiconductors for power conversion applications. Prior to joining ARL, Ron worked with Motorola Corporation in Phoenix, Arizona as a manufacturing engineer, and then later as a process engineer for ON Semiconductor. At ON, Ron made significant contributions to the successful startup of a 150 mm silicon rectifier fab in Guadalajara, Mexico, and the successful technology transfer of key processes into ON's factory in Roznov, Czech Republic. In 2010, Ron was awarded the Department of the Army's Research and Development Achievement Award for Technical Excellence in the successful development, testing, and demonstration of an all-SiC MOSFET power converter. Ron holds his B.S. in Electrical Engineering, and D.E. in Electrical Engineering from Morgan State University. Ron also serves on the Advisory Board in the Department of Electrical and Computer Engineering at Morgan State. He has published a number of journal and conference papers and his research interests are power semiconductor device testing and modeling, device reliability physics, and the development of suitable testing methods for standardization of WBG power components designed for military, space, and industrial applications.